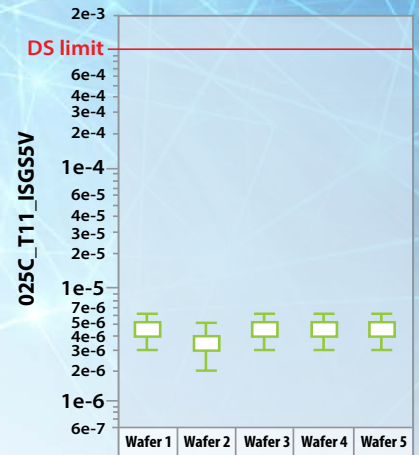


GaN Device Test Information

EPC has partnered with **Spirit Electronics** to provide an expanded range of manufacturing lot specific data services. The below table details the services available. If you have specific requirements not addressed in the table below, please contact us at info@epc-co.com

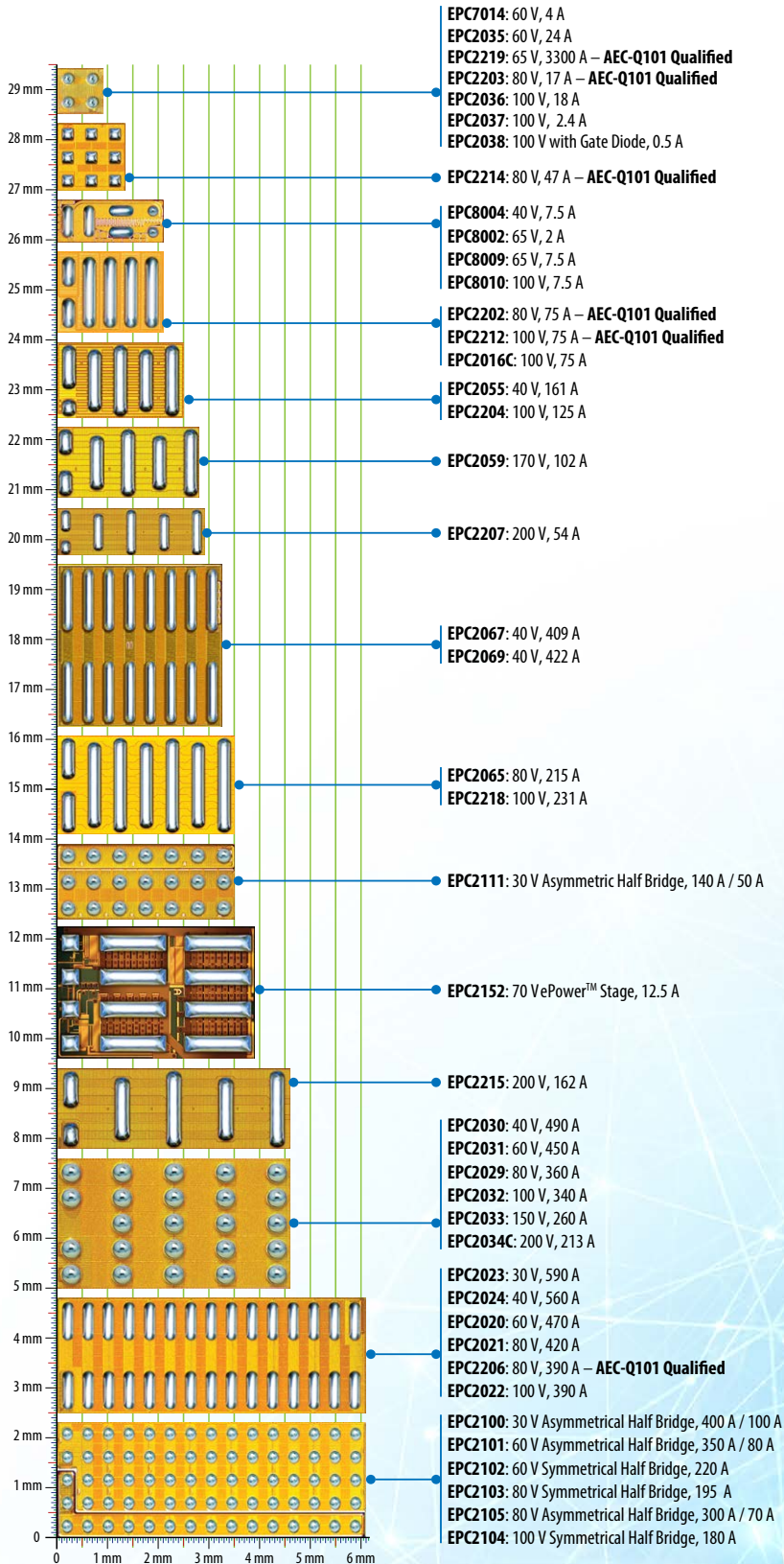
Variability Gauge
Variability Chart for 025C_T11_ISGS5V



Data Pack Offering for EPC Commercial Devices

Data Pack	Description	Test Parameter	Data Type	Temperature
Lot Data Pack	Lot on tape and reel. Data pack of electrical distribution for the lot (mean, standard deviation, min, max).	I_{DSS} (Drain-Source Leakage)	Mean, Std Dev, Min, Max	25°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
Serialized Lot Data Pack	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 25°C data.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	25°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
Serialized Lot Data Pack - HighTemp	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, sample probe at 150°C, data pack at 90°C.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	150°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
Serialized Lot Data Pack - LowTemp	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, -55°C data.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	-55°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
Serialized Lot Data Pack with Visual	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, 25°C data. Die visual inspection sample data.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	25°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A
Serialized Lot Data Pack with Visual - HighTemp	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, sample probe at 150°C, data pack at 90°C. Die Visual inspection sample data.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	150°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A
Serialized Lot Data Pack with Visual - LowTemp	Die in tape and reel with individual identification. Serialized data pack of electrical test data for each die, -55°C data. Die visual inspection sample data.	I_{DSS} (Drain-Source Leakage)	Serialized Read & Record	-55°C
		I_{GSS5V} (Gate-to-Source Forward Leakage)		
		I_{GSSmV} (Gate-to-Source Reverse Leakage) - When Applicable		
		$V_{GS(TH)}$ (Gate Threshold Voltage)		
		$R_{DS(on)}$ Drain-Source On Resistance		
		Visual Inspection Sample Data	Serialized Photo Records	N/A

For information on pricing and availability please contact [Spirit Electronics](http://www.spirit-electronics.com)



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